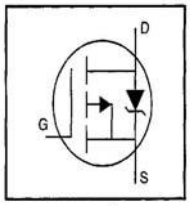
PD- 95414

International
IOR Rectifier
HEXFET® Power MOSFET

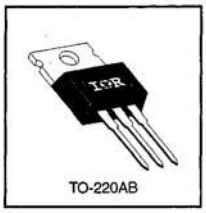
IRF9620PbF



V_{DSS} = -200V

$R_{DS(on)}$ = 1.5Ω

I_D = -3.5A



- Dynamic dv/dt Rating
- P-Channel
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Lead-Free

Description

The HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry and unique processing of the HEXFET design achieve very low on-state resistance combined with high transconductance and extreme device ruggedness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

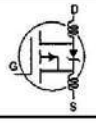
Absolute Maximum Ratings

	Parameter	Max.	Units
I_D @ T_C = 25°C	Continuous Drain Current, V_{GS} @ -10 V	-3.5	A
I_D @ T_C = 100°C	Continuous Drain Current, V_{GS} @ -10 V	-2.0	
I_{DM}	Pulsed Drain Current ①	-14	
P_D @ T_C = 25°C	Power Dissipation	40	W
	Linear Derating Factor	0.32	W/°C
V_{GS}	Gate-to-Source Voltage	±20	V
I_{LM}	Inductive Current, Clamp	-14	A
dv/dt	Peak Diode Recovery dv/dt ③	-5.0	V/ns
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)	

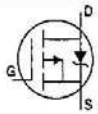
Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	—	3.1	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	—	0.50	—	
$R_{\theta JA}$	Junction-to-Ambient	—	—	62	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	-200	—	—	V	V_{GS}=0V, I_D=-250µA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	-0.22	—	V/°C	Reference to 25°C, I_D=-1mA
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	—	1.5	Ω	V_{GS}=-10V, I_D=-1.5A ④
$V_{GS(th)}$	Gate Threshold Voltage	-2.0	—	-4.0	V	V_{DS}=V_{GS}, I_D=-250µA
g_{fs}	Forward Transconductance	1.0	—	—	S	V_{DS}=-50V, I_D=-1.5A ④
I_{DSS}	Drain-to-Source Leakage Current	—	—	-100	µA	V_{DS}=-200V, V_{GS}=0V
		—	—	-500		V_{DS}=-160V, V_{GS}=0V, T_J=125°C
I_{GSS}	Gate-to-Source Forward Leakage	—	—	-100	nA	V_{GS}=-20V
	Gate-to-Source Reverse Leakage	—	—	100		V_{GS}=20V
Q_g	Total Gate Charge	—	—	22	nC	I_D=-4.0A
Q_{gs}	Gate-to-Source Charge	—	—	12		V_{DS}=-160V
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	10		V_{GS}=-10V See Fig. 11 & 18 ④
$t_{d(on)}$	Turn-On Delay Time	—	15	—	ns	V_{DD}=-100V
t_r	Rise Time	—	25	—		I_D=-1.5A
$t_{d(off)}$	Turn-Off Delay Time	—	20	—		R_G=50Ω
t_f	Fall Time	—	15	—		R_D=67Ω See Figure 17 ④
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6 mm (0.25in.) from package and center of die contact 
L_S	Internal Source Inductance	—	7.5	—		
C_{iss}	Input Capacitance	—	350	—	pF	V_{GS}=0V
C_{oss}	Output Capacitance	—	100	—		V_{DS}=-25V
C_{rss}	Reverse Transfer Capacitance	—	30	—		f=1.0MHz See Figure 10

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I_S	Continuous Source Current (Body Diode)	—	—	-3.5	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	-14		
V_{SD}	Diode Forward Voltage	—	—	-7.0	V	T_J=25°C, I_S=-3.5A, V_{GS}=0V ④
t_{rr}	Reverse Recovery Time	—	300	450	ns	T_J=25°C, I_F=-3.5A
Q_{rr}	Reverse Recovery Charge	—	1.9	2.9	µC	di/dt=100A/µs ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is neglegible (turn-on is dominated by L_S+L_D)				

Notes:

① Repetitive rating; pulse width limited by max. junction temperature (See Figure 5)

② Not Applicable

③ I_{SD}≤-3.5A, di/dt≤95A/µs, V_{DD}≤$V_{(BR)DSS}$, T_J≤150°C

④ Pulse width ≤ 300 µs; duty cycle ≤2%.

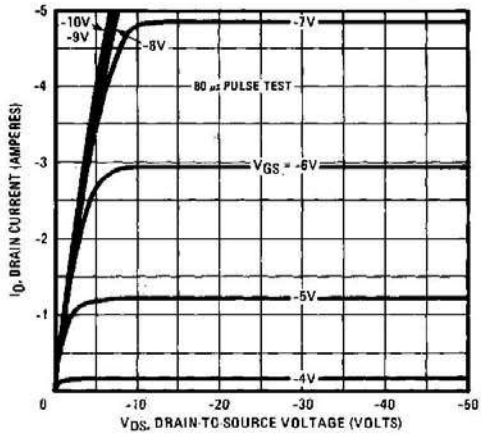


Fig. 1 — Typical Output Characteristics

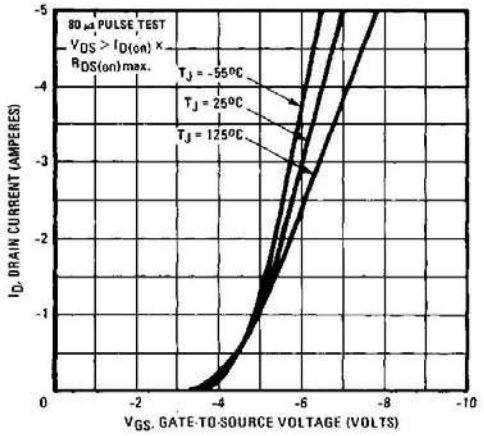


Fig. 2 — Typical Transfer Characteristics

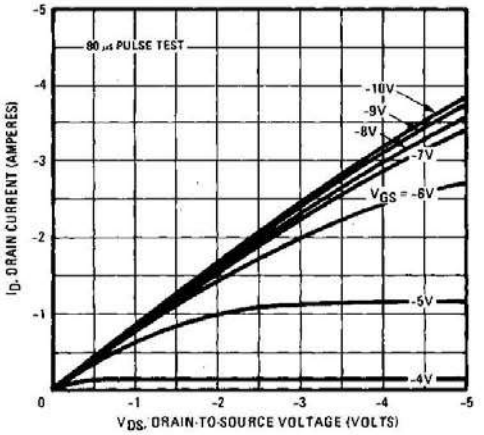


Fig. 3 — Typical Saturation Characteristics

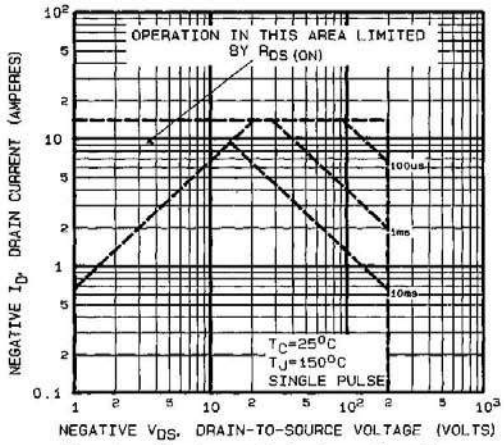


Fig. 4 — Maximum Safe Operating Area

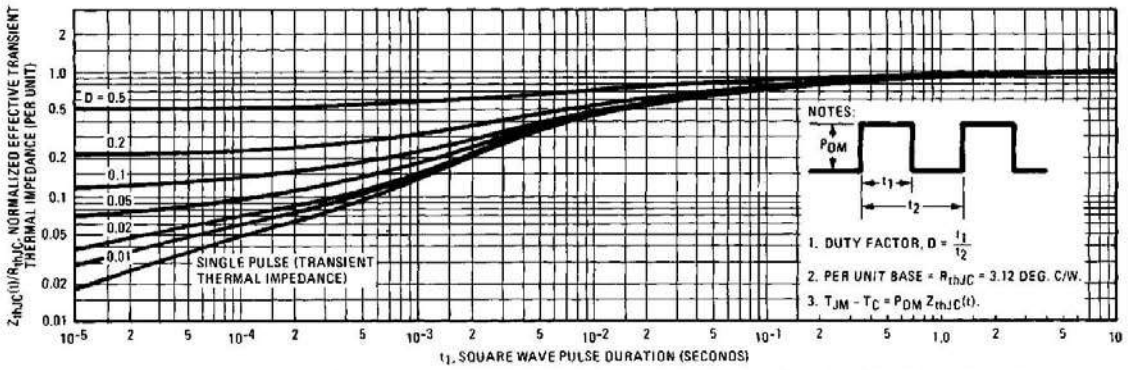


Fig. 5 — Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

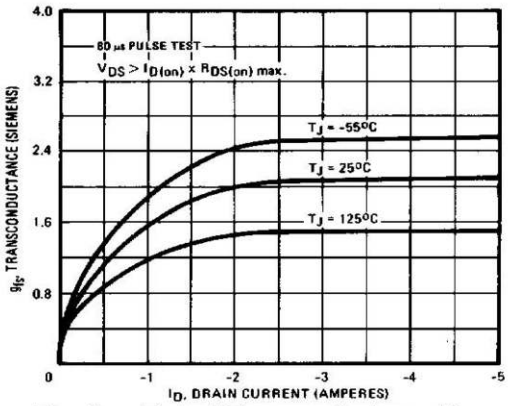


Fig. 6 — Typical Transconductance Vs. Drain Current

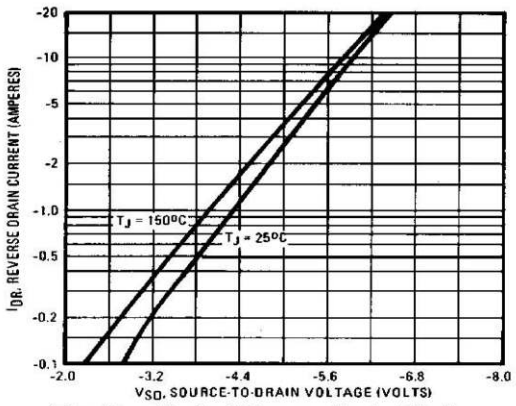


Fig. 7 — Typical Source-Drain Diode Forward Voltage

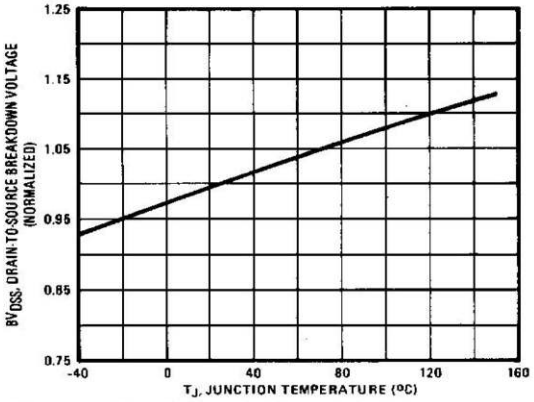


Fig. 8 — Breakdown Voltage Vs. Temperature

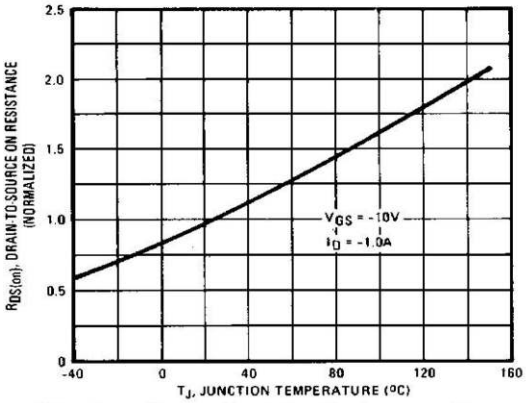


Fig. 9 — Normalized On-Resistance Vs. Temperature

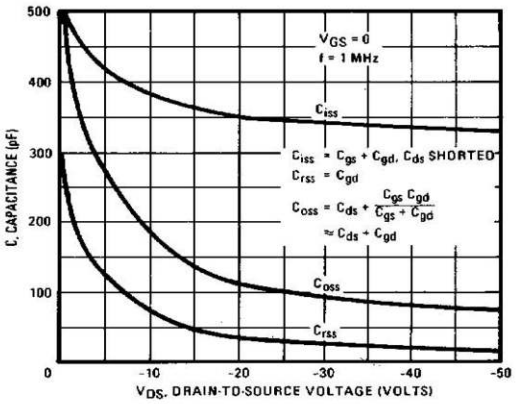


Fig. 10 — Typical Capacitance Vs. Drain-to-Source Voltage

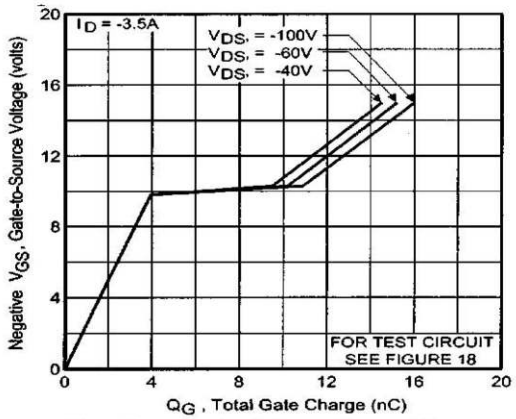


Fig. 11 — Typical Gate Charge Vs. Gate-to-Source Voltage

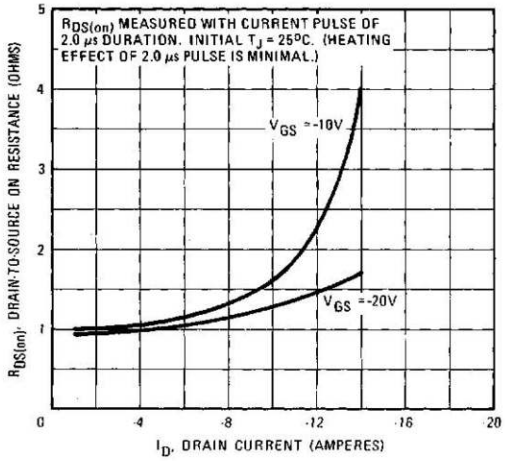


Fig. 12 — Typical On-Resistance Vs. Drain Current

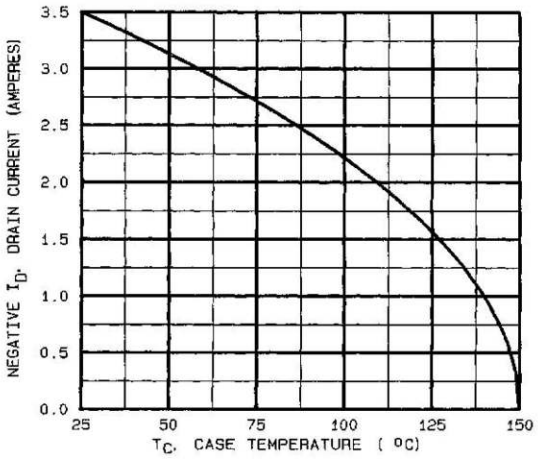


Fig. 13 — Maximum Drain Current Vs. Case Temperature

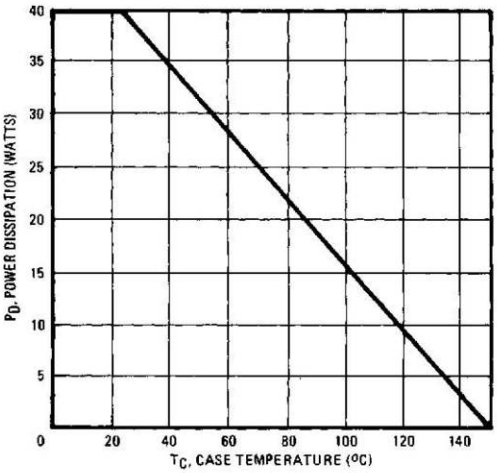


Fig. 14 — Power Vs. Temperature Derating Curve

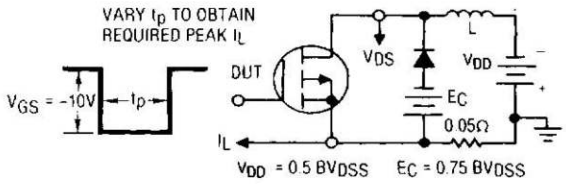


Fig. 15 — Clamped Inductive Test Circuit

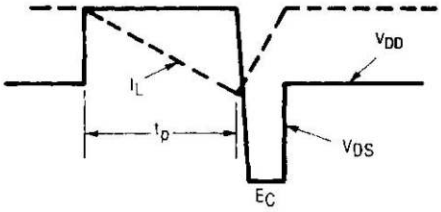


Fig. 16 — Clamped Inductive Waveforms

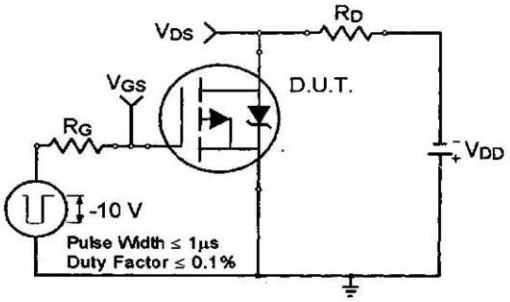


Fig. 17a — Switching Time Test Circuit

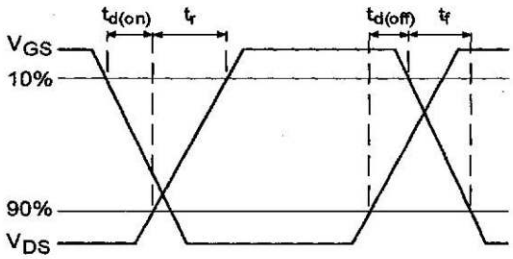


Fig. 17b — Switching Time Waveforms

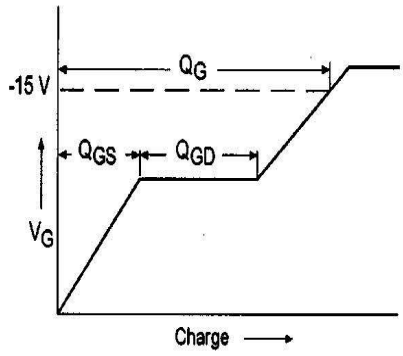


Fig. 18a — Basic Gate Charge Waveform

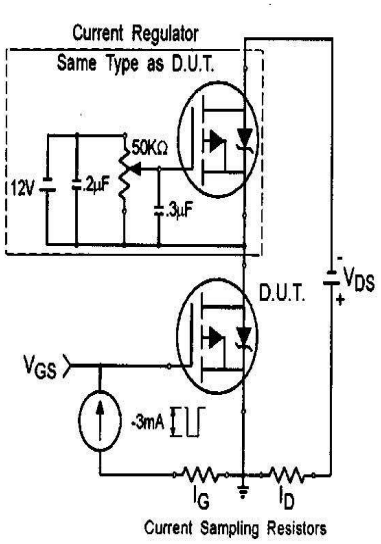
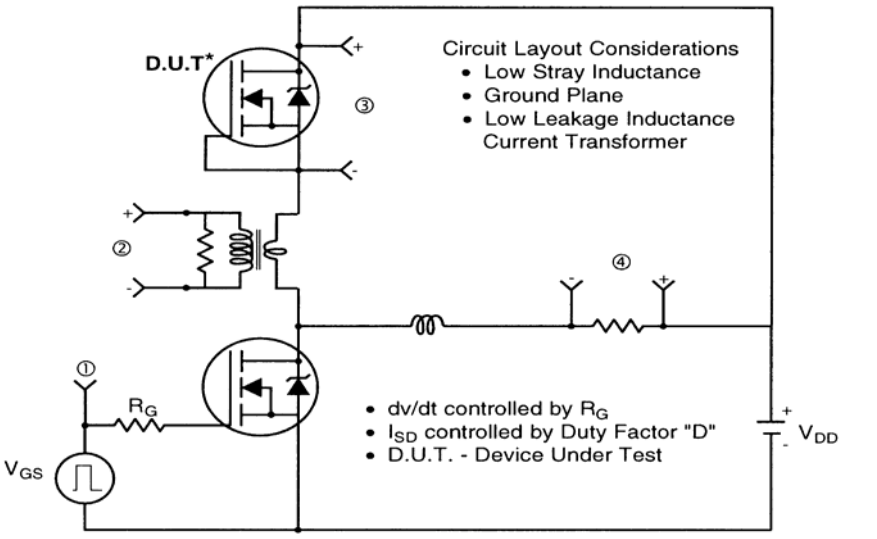
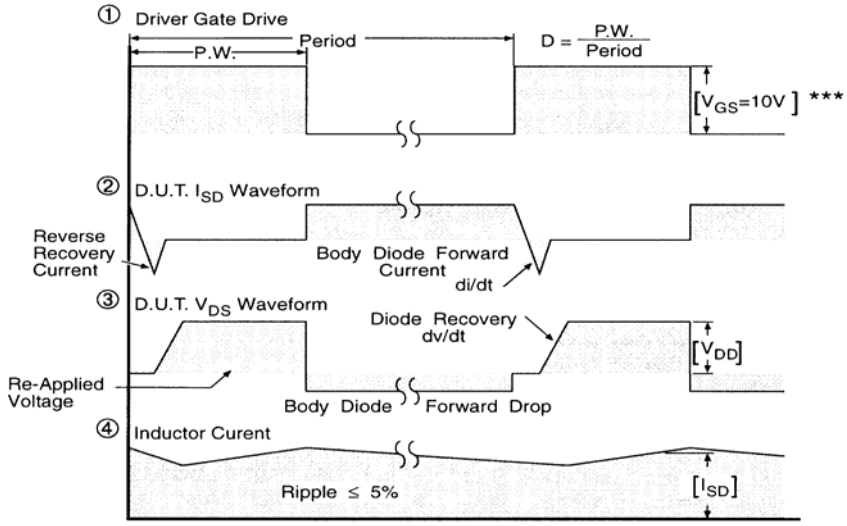


Fig. 18b — Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



* Reverse Polarity of D.U.T for P-Channel

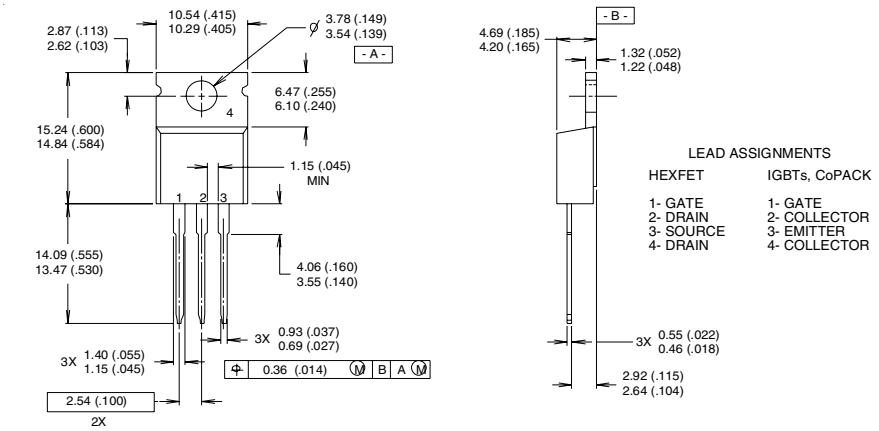


*** V_{GS} = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For P-Channel HEXFETS

TO-220AB Package Outline

Dimensions are shown in millimeters (inches)



LEAD ASSIGNMENTS

HEXFET	IGBTs, CoPACK
1- GATE	1- GATE
2- DRAIN	2- COLLECTOR
3- SOURCE	3- EMITTER
4- DRAIN	4- COLLECTOR

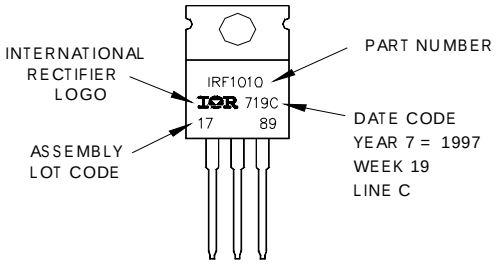
NOTES:

1 DIMENSIONING & TOLERANCING PER ANSI Y14.5M, 1982.
2 CONTROLLING DIMENSION : INCH
3 OUTLINE CONFORMS TO JEDEC OUTLINE TO-220AB.
4 HEATSINK & LEAD MEASUREMENTS DO NOT INCLUDE BURRS.

TO-220AB Part Marking Information

EXAMPLE: THIS IS AN IRF1010
LOT CODE 1789
ASSEMBLED ON WW 19, 1997
IN THE ASSEMBLY LINE "C"

Note: "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.

International
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06/04

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